

Docket No.: P2000,0322 D

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Michael Hübner et al.
Div. of Applic. No. : 10/010,504, filed December 5, 2001
Div. filed : December 15, 2003
Title : Method and Probe Card Configuration for Testing a Plurality of
Integrated Circuits in Parallel
Examiner : Ernest F. Karlsen Group Art Unit: 2829

Hon. Commissioner for Patents
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

In accordance with 37 C.F.R. 1.98, the following patents and/or publications are cited herewith:

U.S. Patent No. 6,064,213 (Khandros et al.), dated May 16, 2000;

German Published, Non-Prosecuted Patent Application No. DE 198 26 314 A1 (Hayama et al.), dated December 24, 1998.

The above-mentioned references were cited in an *Information Disclosure Statement* dated December 5, 2001, in parent application No. 10/010,504.

U.S. Patent No. 4,585,991 (Reid et al.), dated April 1986;

U.S. Patent No. 5,070,297 (Kwon et al.), dated December 1991;

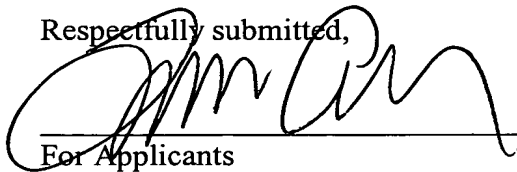
U.S. Patent No. 5,497,079 (Yamada et al.), dated March 1996;

U.S. Patent No. 5,929,651 (Leas et al.), dated July 1999;

U.S. Patent No. 6,205,654 (Burns), dated March 2001.

The above-mentioned references were cited in an Office Action dated April 14, 2003, in parent application No. 10/010,504.

Respectfully submitted,



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For Applicants

Date: December 15, 2003

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FORM PTO-1449 (SUBSTITUTE) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b))				Attorney Docket No.: P2000,0322 D Divisional of Applic. No. 10/010,504 Applicant Michael Hübner et al. Filing Date of Divisional Group Art Unit December 15, 2003 2829			
EXAMINER INITIALS	PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE	
	A	6,064,213	05/00	Khandros et al.			
	B	4,585,991	04/86	Reid et al.			
	C	5,070,297	12/91	Kwon et al.			
	D	5,497,079	03/96	Yamada et al.			
	E	5,929,651	07/99	Leas et al.			
	F	6,205,654	03/01	Burns			
	G						
	H						
	I						
FOREIGN PATENT DOCUMENT							
	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES NO	
	J	DE 198 26 314 A1	12/98	Germany			
	K						
	L						
	M						
	N						
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
EXAMINER				DATE CONSIDERED			
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							